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**Semiconductor integrated circuit has terminals for measuring characteristics of its elements, and control section for outputting selection address signal for selectively connecting each element to be measured to the terminals**

Patent Assignee: NEC CORP (NIDE )

Inventor: OHKAWA S

Number of Countries: 028    Number of Patents: 004

Patent Family:

Patent No	Kind	Date	Applicat No	Kind	Date	Week
EP 1085331	A2	20010321	EP 2000119667	A	20000908	200143 B
CN 1288160	A	20010321	CN 2000127078	A	20000914	200143
JP 2001083214	A	20010330	JP 99260677	A	19990914	200143
KR 2001030330	A	20010416	KR 200053316	A	20000908	200163

Priority Applications (No Type Date): JP 99260677 A 19990914

Patent Details:

Patent No	Kind	Lan	Pg	Main IPC	Filing Notes
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EP 1085331	A2	E	19	G01R-031/26	
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Designated States (Regional): AL AT BE CH CY DE DK ES FI FR GB GR IE IT

LI LT LU LV MC MK NL PT RO SE SI

CN 1288160	A			G01R-031/28	
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JP 2001083214	A		10	G01R-031/28	
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KR 2001030330	A			G01R-031/26	
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Abstract (Basic): EP 1085331 A2

NOVELTY - Semiconductor integrated circuit comprises elements to be measured (11); characteristic measurement terminals (13) for measuring the characteristics of the elements; and a control section for outputting a selection address signal for selectively connecting each element to be measured to the characteristic measurement terminals. The control section is a counter which is driven by a scanning signal used in the characteristic measurement and which automatically generates the selection address signal.

DETAILED DESCRIPTION - INDEPENDENT CLAIM is also included for the following:

(a) method of measuring the characteristics of a semiconductor integrated circuit

USE - For semiconductor integrated circuit.

ADVANTAGE - Require minimum test terminals for measuring the characteristics of devices to be measured, so as to easily form the necessary terminals in a peripheral area of the chip. Does not require an external control device for controlling the generation of the selection address signals.

DESCRIPTION OF DRAWING(S) - The diagram shows the general structure of a semiconductor integrated circuit

devices (11)

measurement terminals (13)

counter section (14)

pp; 19 DwgNo 1/12

Title Terms: SEMICONDUCTOR; INTEGRATE; CIRCUIT; TERMINAL; MEASURE;

CHARACTERISTIC; ELEMENT; CONTROL; SECTION; OUTPUT; SELECT; ADDRESS;

SIGNAL; SELECT; CONNECT; ELEMENT; MEASURE; TERMINAL

Derwent Class: S01; U11

International Patent Class (Main): G01R-031/26; G01R-031/28

International Patent Class (Additional): H01L-021/66  
File Segment: EPI

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